

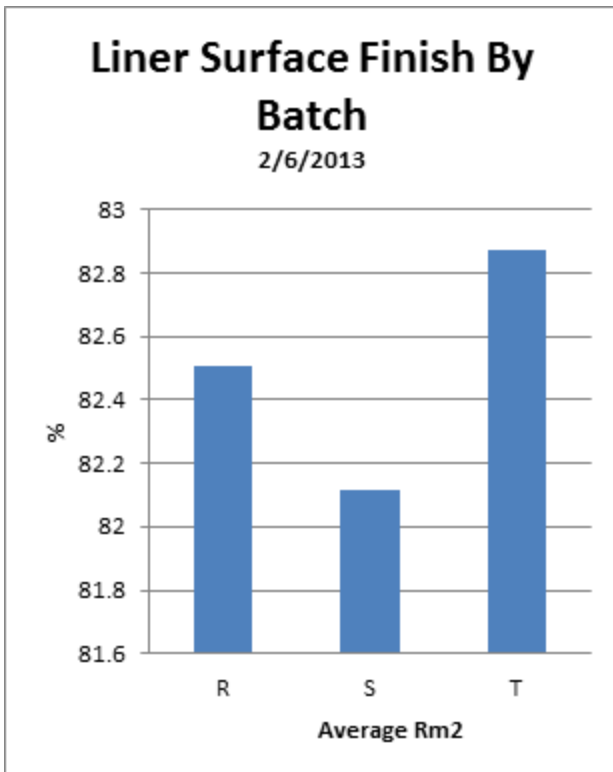
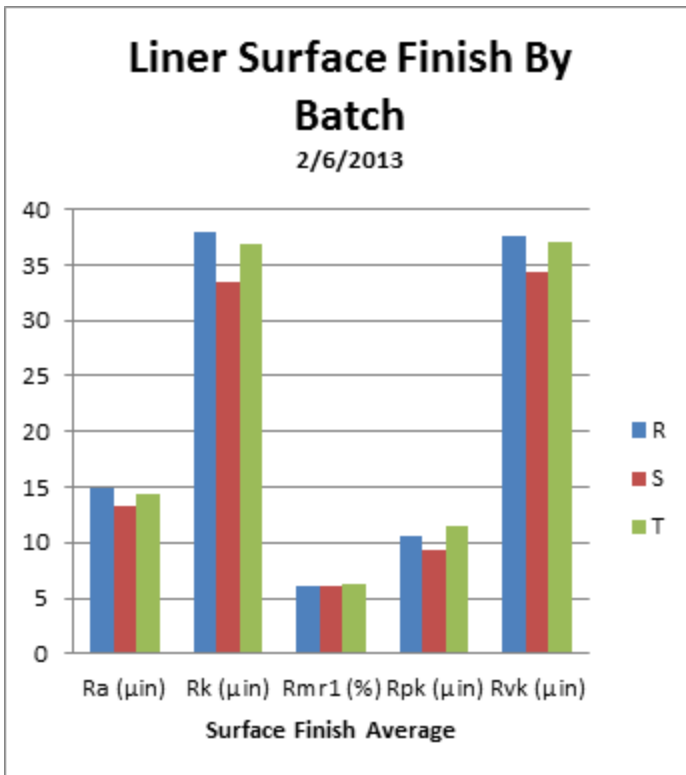
From: [Mark Sutherland](#)
To: [Cooper, Mark \(MAWC\)](#); ["Abi-Akar, Hind"](#); [Alessi, Michael \(michael.l.alessi@exxonmobil.com\)](#); [Anderson, Chuck](#); [Athey, Allison](#); [Bea, Douglas \(DOBE\)](#); [Berman, David \(bermad@cpchem.com\)](#); ["jason.bieneman@us.mahle.com"](#); [Zack Bishop](#); [Boese, Doyle \(Doyle.Boese@Infineum.com\)](#); ["Bond, Stacy"](#); [Booth, James E.](#); [Ron Buck](#); ["Budd, Arnel"](#); ["Buscher, Bill"](#); ["Campbell, Bob"](#); [Carabell, Kevin \(kedc\) \(KCarabell\)](#); [Carter, Brad \(bradley.carter@intertek.com\)](#); ["Carter, James"](#); ["Castanien, Chris"](#); [Cauley, Chris](#); [Jeff Clark](#); ["Conti, Riccardo"](#); ["Devlin, Cathy"](#); ["Fetterman, Pat"](#); [Franklin, Joe \(Intertek\)](#); ["Goshorn, Ken"](#); [Rich Grundza](#); ["Gutzwiller, Jim"](#); [Haeqlin, John \(Intertek\)](#); [Highum, Eric](#); ["Jones, Ron"](#); ["Kennedy, Steve"](#); ["Kersey, Victor"](#); [Kleijwegt, Peter \(pekl\)](#); ["Larch, Bill"](#); ["Lu, WenTong"](#); ["Matasic, Jim"](#); [McGeehan, James](#); [Menasco, Michael \(ENAS\)](#); ["Miiller, Greg"](#); ["Minotti, Michael"](#); [Moritz, Jim \(Intertek\)](#); [Sean A. Moyer](#); ["Nann, Norbert"](#); [Parsons, Gary](#); ["Passut, Charlie"](#); ["Polley, Kris"](#); ["Pridemore, Dan"](#); ["Rajakumar, Allison"](#); [Rele, ter, Ruud \(RUUD\)](#); [Richards, Scott M. \(srichards\) \(SwRI\)](#); [Ritchie, Andrew \(Andrew.Ritchie@Infineum.com\)](#); [Rutherford, Jim \(JARU\)](#); [Salgueiro, Bob \[Bob.Salgueiro@Infineum.com\]](#); [Santos, Elisa](#); ["Schweitzer, Addison"](#); ["Selby, Keith"](#); ["Shank, Greg"](#); [Sztenderowicz, Mark](#); ["Urbanak, Matt"](#); [Tomforde, Jeremy](#); [Van Dam, Wim \(WVDA\)](#); [VanScoyoc, Jonathan \(vanscj@cpchem.com\)](#); ["Weber, Ben"](#); [Wong, Andrew P](#)
Subject: RE: Mack Surveillance Panel Teleconference - Thursday, February 7, 2013, 10:30 AM - Noon Eastern
Date: Thursday, February 07, 2013 7:59:30 AM
Attachments: [image002.png](#)
[image009.png](#)
[image010.png](#)

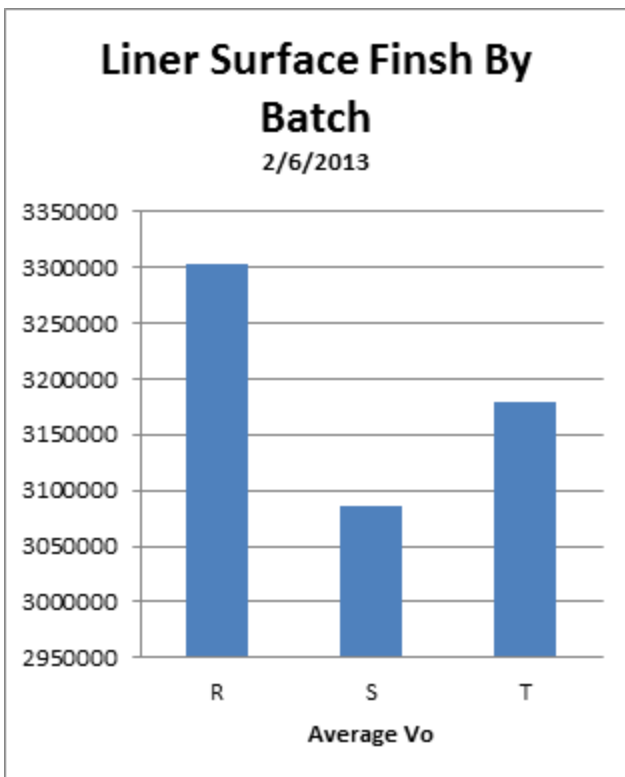
All,

Below are the Liner surface finish measurement averages and standard deviations by liner batch. We added the 3 extra R liners.

Liner Batch Average Measurements for R, S and T liners

Batch	R Liners (n=5)		S Liners (n=2)		T Liners (n=72)	
	Average	SD	Average	SD	Average	SD
Ra μin	14.9	1.7	13.3	1.0	14.3	1.2
Rk μin	37.9	3.4	33.4	1.7	36.8	2.6
Rmr1 %	6.1	0.4	6.1	0.4	6.3	0.5
Rmr2 %	82.5	1.1	82.1	1.7	82.9	1.0
Rpk μin	10.6	1.2	9.4	1.6	11.5	2.4
Rvk μin	37.6	5.8	34.3	3.8	37.0	5.8
Vo (μin*μin)/in	3302250	621462	3086081	588103	3179478	549575





Regards,
Mark



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Cell: (210) 867-8357
Fax: (210) 690-1959

From: Cooper, Mark (MAWC) [mailto:MAWC@chevron.com]
Sent: Tuesday, February 05, 2013 9:33 AM
To: 'Abi-Akar, Hind'; Alessi, Michael (michael.l.alessi@exxonmobil.com); Anderson, Chuck; Athey, Allison; Bea, Douglas (DOBE); Berman, David (bermadl@cpchem.com); 'jason.bieneman@us.mahle.com'; Zack Bishop; Boese, Doyle (Doyle.Boese@Infineum.com); 'Bond, Stacy'; Booth, James E.; Ron Buck; 'Budd, Armel'; 'Buscher, Bill'; 'Campbell, Bob'; Carabell, Kevin (kedc) (KCarabell); Carter, Brad (bradley.carter@intertek.com); 'Carter, James'; 'Castanien, Chris'; Cauley, Chris; 'Clark, Jeff'; 'Conti, Riccardo'; Cooper, Mark (MAWC); 'Devlin, Cathy'; 'Fetterman, Pat'; Franklin, Joe (Intertek); 'Goshorn, Ken'; 'Grundza, Rich'; 'Gutzwiller, Jim'; Haeglin, John (Intertek); Highum, Eric; 'Jones, Ron'; 'Kennedy, Steve'; 'Kersey, Victor'; Kleijwegt, Peter (pekI); 'Larch, Bill'; 'Lu, WenTong'; 'Matasic, Jim'; McGeehan, James; Menasco, Michael (ENAS); 'Miiller, Greg'; 'Minotti, Michael'; Moritz, Jim (Intertek); Moyer, Sean (sam@astmtmc.cmu.edu); 'Nann, Norbert'; Parsons, Gary; 'Passut, Charlie';

'Polley, Kris'; 'Pridemore, Dan'; 'Rajakumar, Allison'; Rele, ter, Ruud (RUUD); Richards, Scott M. (srichards) (SwRI); Ritchie, Andrew (Andrew.Ritchie@Infineum.com); Rutherford, Jim (JARU); Salgueiro, Bob [Bob.Salgueiro@Infineum.com]; Santos, Elisa; 'Schweitzer, Addison'; 'Selby, Keith'; 'Shank, Greg'; Mark Sutherland; Sztenderowicz, Mark; 'Urbanak, Matt'; Tomforde, Jeremy; Van Dam, Wim (WVDA); VanScoyoc, Jonathan (vanscj@cpchem.com); 'Weber, Ben'; Wong, Andrew P

Subject: Mack Surveillance Panel Teleconference - Thursday, February 7, 2013, 10:30 AM - Noon Eastern

Our next Mack Surveillance Panel teleconference will be held on Thursday, February 7, 2013, from 10:30 AM - Noon Eastern.

Agenda

T-12 liner surface specifications

Status of T-11 reference tests on 'tweaked' Oil 822

Status and availability of T-12 and T-11 tests

Dial-in number and passcode are shown below.

877-344-4239

483093#

Thanks

Mark Cooper, AEO Development

Chevron Oronite Company LLC

4502 Centerview Dr, Suite 210

San Antonio, Texas 78228

Tel 210-731-5606 Cell 210-867-8606 Fax 210-731-5699

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